

OP27A/C/E/G, OP37A/C/E/G

Low-Noise High-Speed Precision Operational Amplifier

The OP27 and OP37 operational amplifiers combine outstanding noise performance with excellent precision and high-speed specifications. The wideband noise is only 3 nV/ \sqrt{Hz} and with the 1/f noise corner at 2.7 Hz, low noise is maintained for all low-frequency applications.

The outstanding characteristics of the OP27 and OP37 make these devices excellent choices for low-noise amplifier applications requiring precision performance and reliability. Additionally, the OP37 is free of latch-up in high-gain, large-capacitive-feedback configurations.

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-38535
 - Class Q Military
 - Class V Space Level

• Qualified Suppliers List of Distributors (QSLD)

• Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

 Direct Replacements for PMI and LTC OP27 and OP37 Series

Features of OP27A, OP27C, OP37A, and OP37C:

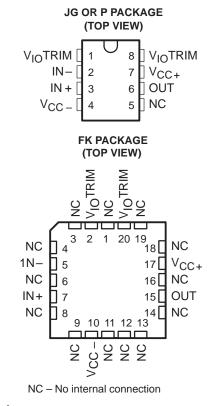
- Maximum Equivalent Input Noise Voltage: 3.8 nV/\Hz at 1 kHz 5.5 nV/\Hz at 10 kHz
- Very Low Peak-to-Peak Noise Voltage at 0.1 Hz to 10 Hz ... 80 nV Typ
- Low Input Offset Voltage ... 25 μV Max
- High Voltage Amplification ... 1 V/µV Min Feature of OP37 Series:
- Minimum Slew Rate ... 11 V/μs

description

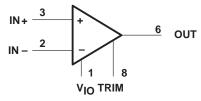
The OP27 and OP37 operational amplifiers combine outstanding noise performance with excellent precision and high-speed specifications. The wideband noise is only 3 nV/ $\sqrt{\text{Hz}}$ and with the 1/f noise corner at 2.7 Hz, low noise is maintained for all low-frequency applications.

The outstanding characteristics of the OP27 and OP37 make these devices excellent choices for low-noise amplifier applications requiring precision performance and reliability. Additionally, the OP37 is free of latch-up in high-gain, large-capacitive-feedback configurations.

The OP27 series is compensated for unity gain. The OP37 series is decompensated for increased bandwidth and slew rate and is stable down to a gain of 5.



symbol



Pin numbers are for the JG and P packages.

The OP27A, OP27C, OP37A, and OP37C are characterized for operation over the full military temperature range of -55° C to 125° C. The OP27E, OP27G, OP37E, and OP37G are characterized for operation from -25° C to 85° C.

AVAILABLE OPTIONS									
	Viemey	STABLE		PACKAGE					
TA	V _{IO} max AT 25°C	GAIN	CERAMIC DIP (JG)	CHIP CARRIER (FK)	PLASTIC DIP (P)				
	25)/	1	—	—	OP27EP				
–25°C to 85°C	25 μV	5	—	—	OP37EP				
-25 C 10 65 C	100)/	1	—	—	OP27GP				
	100 μV	5	—	—	OP37GP				
	25\/	1	OP27AJG	OP27AFK	_				
–55°C to 125°C	25 μV	5	OP37AJG	OP37AFK	—				
-55 C 10 125 C	100	1	OP27CJG	—	—				
	100 μV	5	OP37CJG	_	_				



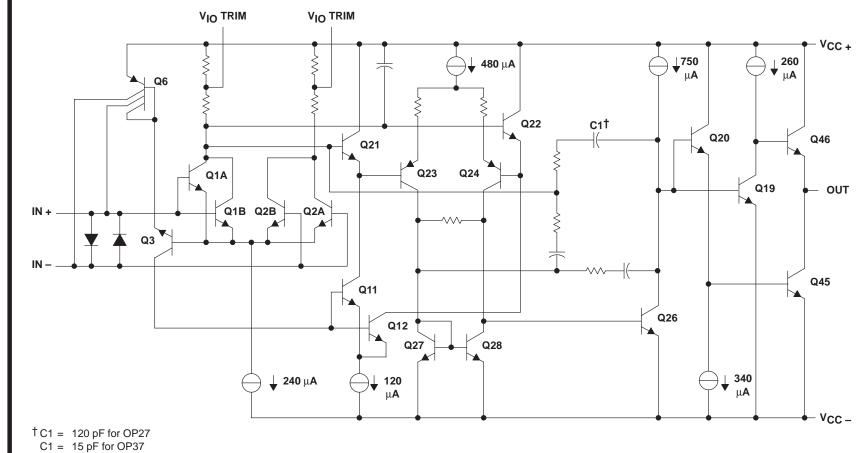
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schematic



OP27A, OP27C, OP27E, OP27G OP37A, OP37C, OP37E, OP37G LOW-NOISE HIGH-SPEED PRECISION OPERATIONAL-AMPLIFIER

Iemplate Release Date: 7–11–94

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC+} (see Note 1)
Supply voltage, V _{CC} (see Note 1) – 22 V
Input voltage, V ₁
Duration of output short circuit unlimited
Differential input current (see Note 2) ±25 mA
Continuous power dissipation
Operating free-air temperature range: OP27A, OP27C, OP37A, OP37C – 55°C to 125°C
OP27E, OP27G, OP37E, OP37G – 25°C to 85°C
Storage temperature range – 65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 60 seconds: JG or FK package
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: P package 260°C

NOTES: 1. All voltage values are with respect to the midpoint between V_{CC+} and V_{CC-} unless otherwise noted.

The inputs are protected by back-to-back diodes. Current-limiting resistors are not used in order to achieve low noise. Excessive
input current will flow if a differential input voltage in excess of approximately ± 0.7 V is applied between the inputs unless some
limiting resistance is used.

PACKAGE	T _A ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 85°C POWER RATING	T _A = 125°C POWER RATING
JG	1050 mW	8.4 mW/°C	546 mW	210 mW
FK	1375 mW	11.0 mW/°C	715 mW	275 mW
Р	1000 mW	8.0 mW/°C	520 mW	N/A

DISSIPATION RATING TABLE



OP27A, OP27C, OP27E, OP27G OP37A, OP37C, OP37E, OP37G LOW-NOISE HIGH-SPEED PRECISION OPERATIONAL-AMPLIFIER

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recommended operating conditions

		OP27A, OP37A			OP2	UNIT		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC+}		4	15	22	4	15	22	V
Supply voltage, V _{CC} _		-4	-15	-22	-4	-15	-22	V
	$V_{CC\pm} = \pm 15 \text{ V}, T_{A} = 25^{\circ}\text{C}$	± 11			±11			V
Common-mode input voltage, VIC	$V_{CC\pm} = \pm 15 \text{ V}, T_A = -55^{\circ}\text{C to } 125^{\circ}\text{C}$	±10.3			±10.2			v
Operating free-air temperature, T_A		-55		125	-55		125	°C

electrical characteristics at specified free-air temperature, V_{CC \pm} = ±15 V (unless otherwise noted)

			TEST CONDITIONS		OP27A, OP37A			OP27C, OP37C			
	PARAMETER	TEST CO	DNDITIONS	TAT	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
14	leave affect welters	$V_{O} = 0,$	$V_{IC} = 0$	25°C		10	25		30	100	
VIO	Input offset voltage	R _S = 50 Ω,	See Note 3	Full range			60			300	μV
ανιο	Average temperature coefficient of input offset voltage			Full range		0.2	0.6		0.4	1.8	μV/°C
	Long-term drift of input offset voltage	See Note 4				0.2	1		0.4	2	μV/mo
lia	Input offset current	$V_{O} = 0,$	$V_{IC} = 0$	25°C		7	35		12	75	nA
IIO	liput onset current	VO = 0,	AIC = 0	Full range			50			135	ΠA
lin	Input bias current $V_{O} = 0$,	$V_{O} = 0,$	$V_{IC} = 0$	25°C		±10	±40		±15	±80	nA
ΙB		VO = 0,	VIC = 0	Full range			±60			±150	
	Common-mode input			25°C	11 to -11			11 to -11			V
	voltage range			Full range	10.3 to -10.3			10.5 to -10.5			v
		$R_L \ge 2 k\Omega$			±12	±13.8		±11.5	±13.5		
VOM	Peak output voltage swing	$R_L \ge 0.6 \ k\Omega$	1]	±10	±11.5		±10	±11.5		V
		$R_L \ge 2 \ k\Omega$		Full range	±11.5			10.5			
		$R_L \ge 2 k\Omega$,	$V_{O} = \pm 10 V$		1000	1800		700	1500		
	Large-signal differential	$R_L \ge 1 \ k\Omega$,	$V_{O} = \pm 10 V$		800	1500			1500		
AVD	voltage amplification	$\begin{array}{l} R_L \geq 0.6 \; \mathrm{k}\Omega \\ V_{CC\pm} = \; \pm \; 4 \end{array}$	$V_{O} = \pm 1 V,$ $V_{V} = \pm 1 V,$		250	700		200	500		V/mV
		$R_L \ge 2 k\Omega$,	$V_{O} = \pm 10 V$	Full range	600			300			
^r i(CM)	Common-mode input resistance					3			2		GΩ
r _o	Output resistance	V _O = 0,	IO = 0	25°C		70			70		Ω
CMRR	Common-mode rejection	$V_{IC} = \pm 11 $ V	/	25°C	114	126		100	120		dB
	ratio	V _{IC} = ±10 \	/	Full range	110			94			uD
k SVR	Supply voltage rejection	$V_{CC\pm} = \pm 4$		25°C	100	120		94	118		dB
~5VK	ratio	$V_{CC\pm} = \pm 4$.5 V to ±18 V	Full range	96			86			uВ

[†] Full range is -55° C to 125° C.

NOTES: 3. Input offset voltage measurements are performed by automatic test equipment approximately 0.5 seconds after applying power. 4. Long-term drift of input offset voltage refers to the average trend line of offset voltage versus time over extended periods after the first 30 days of operation. Excluding the initial hour of operation, changes in VIO during the first 30 days are typically 2.5 µV (see Figure 3).



OP27A, OP27C, OP27E, OP27G OP37A, OP37C, OP37E, OP37G LOW-NOISE HIGH-SPEED PRECISION OPERATIONAL-AMPLIFIER

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recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V _{CC+}		4	15	22	V
Supply voltage, V _{CC} _		-4	-15	-22	V
	$V_{CC\pm} = \pm 15 \text{ V}, \qquad T_A = 25^{\circ}\text{C}$	±11			V
Common-mode input voltage, VIC	$V_{CC\pm} = \pm 15 \text{ V}, \qquad T_A = -55^{\circ}\text{C to } 125^{\circ}\text{C}$	±10.5			v
Operating free-air temperature, TA		-25		85	°C

electrical characteristics at specified free-air temperature, V_{CC \pm} = ±15 V (unless otherwise noted)

	DADAMETER	TEOTO	TEST CONDITIONS		OP	OP27E, OP37E			OP27G, OP37G		
PARAMETER		TEST CONDITIONS		TA	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
\/	Innut offent veltere	$V_{O} = 0,$	VIC = 0	25°C		10	25		30	100	μV
VIO	Input offset voltage		See Note 3	Full range			60			220	μν
αVIO	Average temperature coefficient of input offset voltage			Full range		0.2	0.6		0.4	1.8	μV/°C
	Long-term drift of input offset voltage	See Note 4				0.2	1		0.4	2	μV/m
lio.	Input offset current	$V_{O} = 0,$	$V_{IC} = 0$	25°C		7	35		12	75	nA
10	input onset current	VO = 0,	VIC = 0	Full range			50			135	IIA
IB	Input bias current	$V_{O} = 0,$	$V_{IC} = 0$	25°C		±10	±40		±15	±80	nA
ΊΒ	input bias current	VO = 0,	VIC = 0	Full range			±60			±150	117
. <i>.</i> C	Common-mode input ICR voltage range			25°C	11 to -11			11 to -11			V
VICR				Full range	10.3 to -10.3			10.5 to -10.5			v
	Peak output voltage swing	$R_L \ge 2 \ k\Omega$			±12	±13.8		±11.5	±13.5		
VOM		$R_L \ge 0.6 \ k\Omega$	1		±10	±11.5		±10	±11.5		V
	owing	$R_L \ge 2 \ k\Omega$		Full range	±11.5			10.5			
		$R_L \ge 2 k\Omega$,			1000	1800		700	1500		
	Large-signal differential	$R_L \ge 1 k\Omega$,	$V_{O} = \pm 10 V$		800	1500			1500		
AVD	voltage amplification	$R_{L} \ge 0.6 \text{ k}\Omega$ $V_{CC\pm} = \pm 4$	e, V _O = ±1 V, V		250	700		200	500		V/m\
		$R_L \ge 2 k\Omega$,	$V_{O} = \pm 10 V$	Full range	600	-		450			
^r i(CM)	Common-mode input resistance					3			2		GΩ
r _o	Output resistance	V _O = 0,	l _O = 0	25°C		70			70		Ω
CMRR	Common-mode rejection	$V_{IC} = \pm 11 $	/	25°C	114	126		100	120		dB
	ratio	V _{IC} = ±10 \	/	Full range	110			96			dR
k SVR	Supply voltage rejection	$V_{CC\pm} = \pm 4$		25°C	100	120		94	118		dB
~2VK	ratio	$V_{CC\pm} = \pm 4$.5 V to ±18 V	Full range	96			90			uD

[†]Full range is – 25°C to 85°C.

NOTES: 3. Input offset voltage measurements are performed by automatic test equipment approximately 0.5 seconds after applying power.

4. Long-term drift of input offset voltage refers to the average trend line of offset voltage versus time over extended periods after the first 30 days of operation. Excluding the initial hour of operation, changes in V_{IO} during the first 30 days are typically 2.5 μ V (see Figure 3).



OP27A, OP27C, OP27E, OP27G OP37A, OP37C, OP37E, OP37G LOW-NOISE HIGH-SPEED PRECISION OPERATIONAL-AMPLIFIER

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OP27 operating characteristics over operating free-air temperature range, V_{CC \pm} = ±15 V

	PARAMETER	TEST CON		OP27A, OP27E			OP27C, OP27G			UNIT
	FARAMETER	TEST CON	TEST CONDITIONS		TYP	MAX	MIN	TYP	MAX	
SR	Slew rate	$A_{VD} \ge 1$,	$R_L \ge 2 \ k\Omega$	1.7	2.8		1.7	2.8		V/µs
V _{N(PP)}	Peak-to-peak equivalent input noise voltage	f = 0.1 Hz to 10 Hz, See Figure 34	R _S = 20 Ω,		0.08	0.18		0.09	0.25	μV
		f = 10 Hz,	R _S = 20 Ω		3.5	5.5		3.8	8	
Vn	Equivalent input noise voltage	f = 30 Hz,	R _S = 20 Ω		3.1	4.5		3.3	5.6	nV/√Hz
		f = 1 kHz,	R _S = 20 Ω		3	3.8		3.2	4.5	1
		f = 10 Hz,	See Figure 35		1.5	4		1.5		
I _n	Equivalent input noise current	f = 30 Hz,	See Figure 35		1	2.3		1		pA/√Hz
		f = 1 kHz,	See Figure 35		0.4	0.6		0.4	0.6	
	Gain-bandwidth product	f = 100 kHz		5	8		5	8		MHz

OP37 operating characteristics over operating free-air temperature range, V_{CC\pm} = ±15 V

	PARAMETER	TEST CON	TEST CONDITIONS		37A, OP	37E	OP3	37C, OP	37G	UNIT
	PARAMETER	TESTCON	DITIONS	MIN	TYP	MAX	MIN	TYP	MAX	
SR	Slew rate	$A_{VD} \ge 5$,	$R_L \ge 2 \ k\Omega$	11	17		11	17		V/µs
V _{N(PP)}	Peak-to-peak equivalent input noise voltage	f = 0.1 Hz to 10 Hz, See Figure 34	R _S = 20 Ω,		0.08	0.18		0.09	0.25	μV
		f = 10 Hz,	R _S = 20 Ω		3.5	5.5		3.8	8	
Vn	Equivalent input noise voltage	f = 30 Hz,	R _S = 20 Ω		3.1	4.5		3.3	5.6	nV/√Hz
	voltage	f = 1 kHz,	R _S = 20 Ω		3	3.8		3.2	4.5	1
		f = 10 Hz,	See Figure 35		1.5	4		1.5		
In	Equivalent input noise current	f = 30 Hz,	See Figure 35		1	2.3		1		pA/√Hz
		f = 1 kHz,	See Figure 35		0.4	0.6		0.4	0.6	1
		f = 10 kHz		45	63		45	63		N 41 I-
	Gain-bandwidth product	$A_V \ge 5$,	f = 1 MHz		40			40		MHz



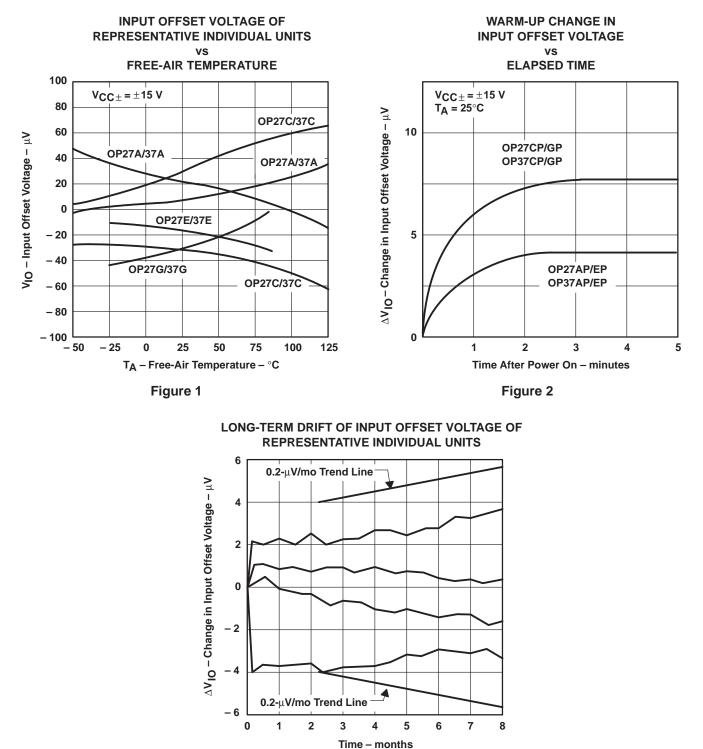
TYPICAL CHARACTERISTICS

Table of Graphs

			FIGURE
VIO	Input offset voltage	vs Temperature	1
Δ٧ΙΟ	Change in input offset voltage	vs Time after power on vs Time (long-term drift)	2 3
10	Input offset current	vs Temperature	4
I _{IB}	Input bias current	vs Temperature	5
VICR	Common-mode input voltage range	vs Supply voltage	6
VOM	Maximum peak output voltage	vs Load resistance	7
V _{O(PP)}	Maximum peak-to-peak output voltage	vs Frequency	8, 9
AVD	Differential voltage amplification	vs Supply voltage vs Load resistance vs Frequency	10 11 12, 13, 14
CMRR	Common-mode rejection ratio	vs Frequency	15
k _{SVR}	Supply voltage rejection ratio	vs Frequency	16
SR	Slew rate	vs Temperature vs Supply voltage vs Load resistance	17 18 19
^ф т	Phase margin	vs Temperature	20, 21
¢	Phase shift	vs Frequency	12, 13
Vn	Equivalent input noise voltage	vs Bandwidth vs Source resistance vs Supply voltage vs Temperature vs Frequency	22 23 24 25 26
I _n	Equivalent input noise current	vs Frequency	27
	Gain-bandwidth product	vs Temperature	20, 21
IOS	Short-circuit output current	vs Time	28
ICC	Supply current	vs Supply voltage	29
	Pulse response	Small signal Large signal	30, 32 31, 33



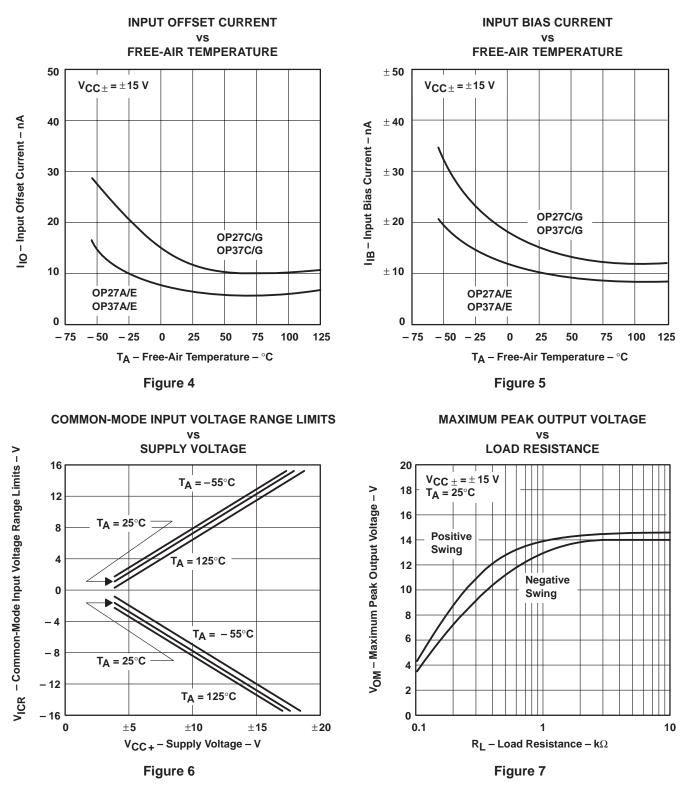
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TYPICAL CHARACTERISTICS[†]

Figure 3

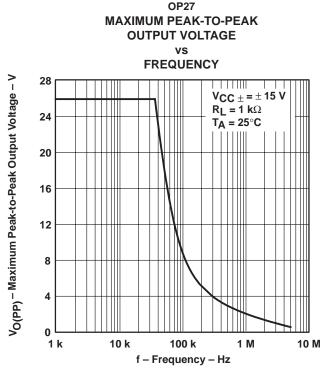


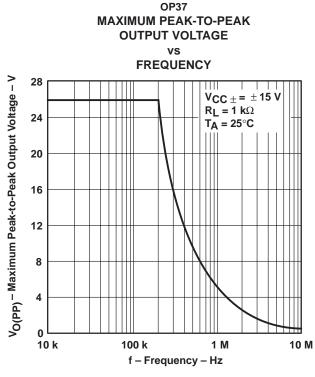


TYPICAL CHARACTERISTICS[†]



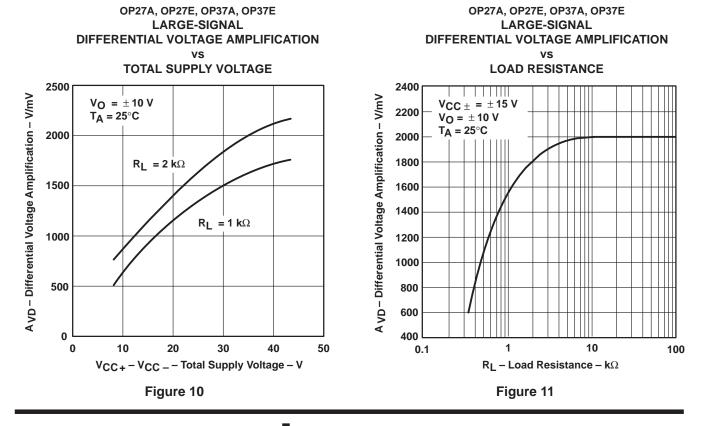
TYPICAL CHARACTERISTICS



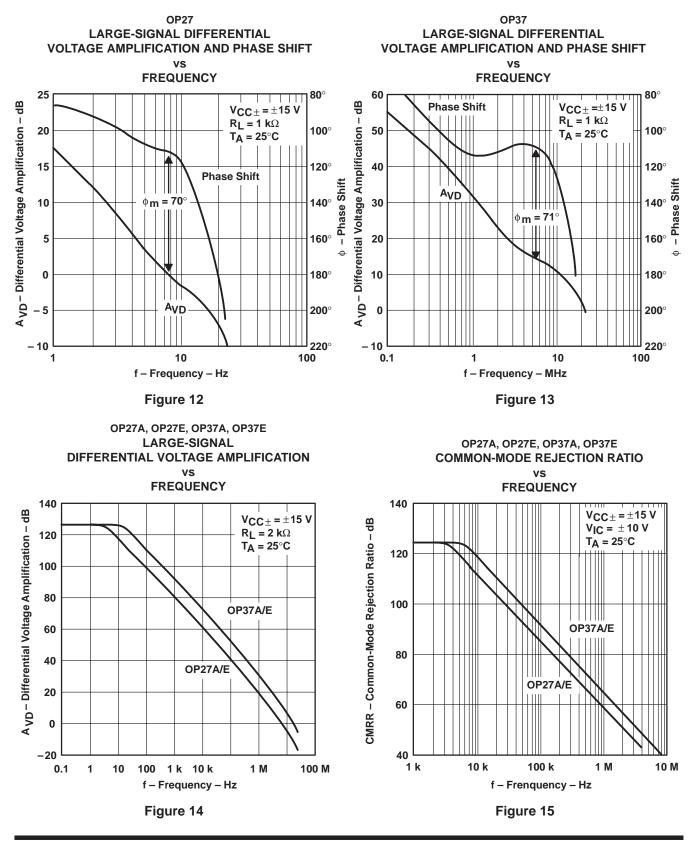








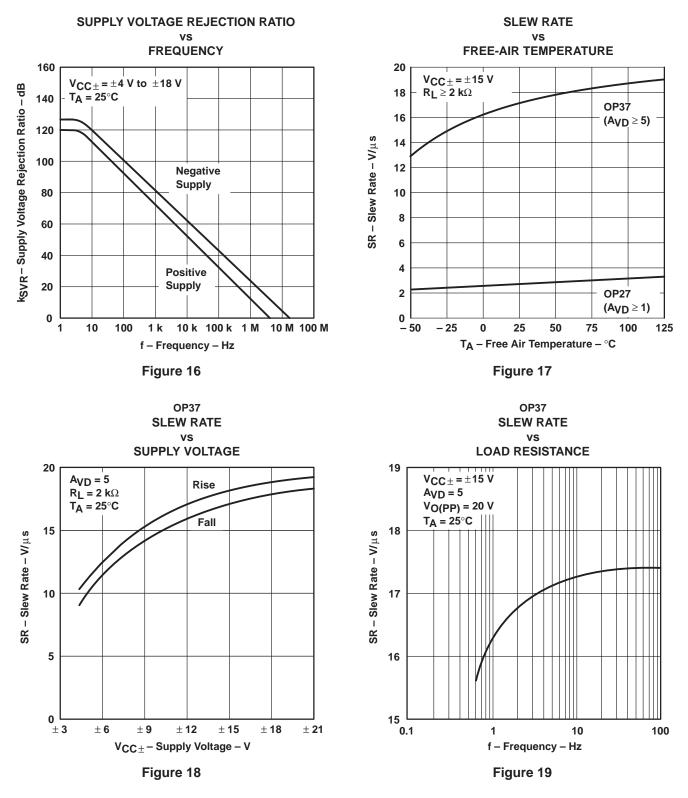




TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS[†]





OP27 OP37 PHASE MARGIN AND PHASE MARGIN AND **GAIN-BANDWIDTH PRODUCT GAIN-BANDWIDTH PRODUCT** vs VS FREE-AIR TEMPERATURE FREE-AIR TEMPERATURE 80 85° 11 $V_{CC\pm} = \pm 15 V$ $V_{CC\pm} = \pm 15 V$ 75 80 85 10.6 фm **70**°
 10.2
 2.01

 9.8
 9.4

 9.4
 9.4

 9
 8.6

 8.2
 8.8

 9
 8.6

 7.8
 7.8
 80 **75**° Gain-Bandwidth Product – MHz **¢m** 65 **70**° 75 ∲m – Phase Margin ¢m – Phase Margin 60° 65° 70 GBW (f = 10 kHz) **60**° 55° 65 **50**° 55° 60 45[°] **50**° 55 GBW (f = 100 kHz) 50 **45**° 7.8 40° **40**° 35° 45 7.4 30° 40 35° 7 - 75 - 50 - 25 25 50 75 100 50 0 125 - 50 - 25 0 25 75 100 125 T_A – Free-Air Temperature – °C T_A – Free-Air Temperature – °C Figure 20 Figure 21

TYPICAL CHARACTERISTICS[†]

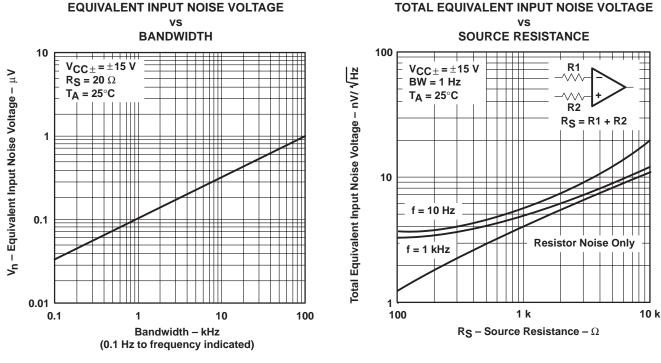
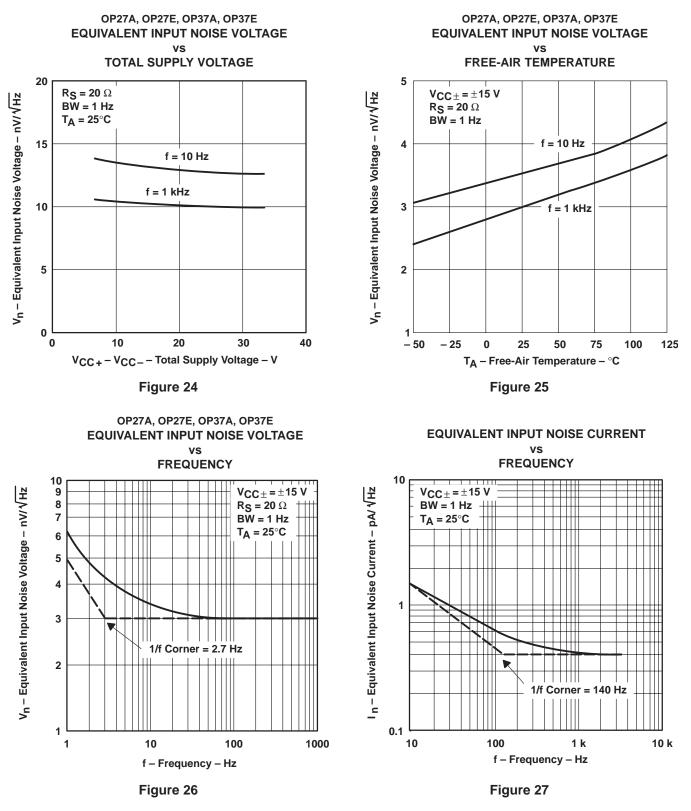


Figure 22

Figure 23

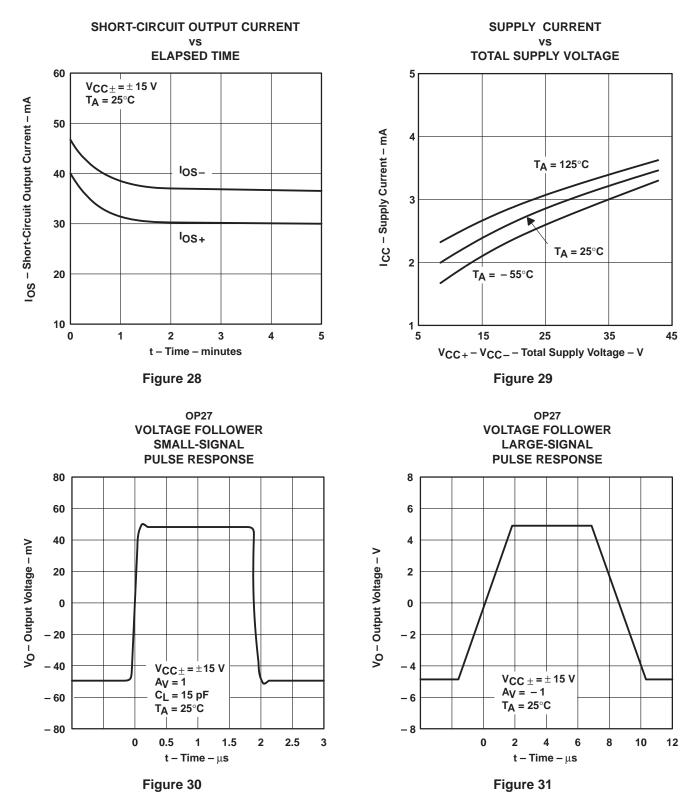


TYPICAL CHARACTERISTICS[†]





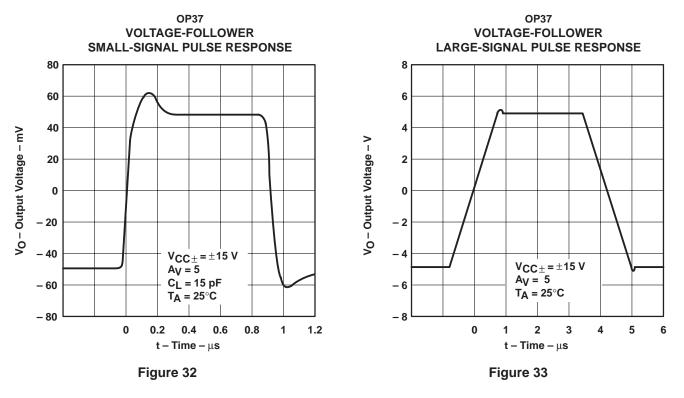
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TYPICAL CHARACTERISTICS[†]



TYPICAL CHARACTERISTICS



APPLICATION INFORMATION

general

The OP27 and OP37 series devices can be inserted directly onto OP07, OP05, μ A725, and SE5534 sockets with or without removing external compensation or nulling components. In addition, the OP27 and OP37 can be fitted to μ A741 sockets by removing or modifying external nulling components.

noise testing

Figure 34 shows a test circuit for 0.1-Hz to 10-Hz peak-to-peak noise measurement of the OP27 and OP37. The frequency response of this noise tester indicates that the 0.1-Hz corner is defined by only one zero. Because the time limit acts as an additional zero to eliminate noise contributions from the frequency band below 0.1 Hz, the test time to measure 0.1-Hz to 10-Hz noise should not exceed 10 seconds.

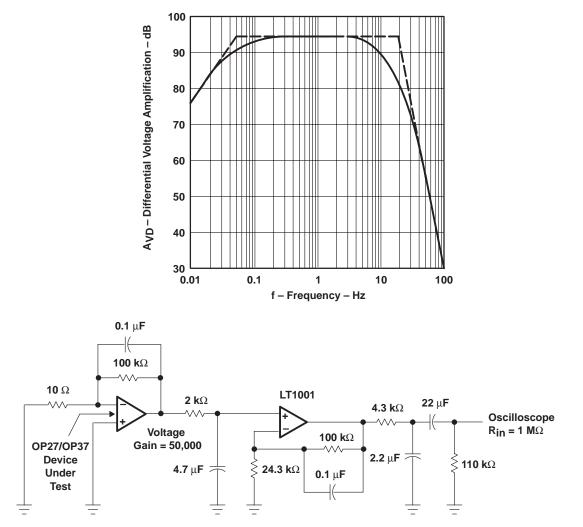
Measuring the typical 80-nV peak-to-peak noise performance of the OP27 and OP37 requires the following special test precautions:

- 1. The device should be warmed up for at least five minutes. As the operational amplifier warms up, the offset voltage typically changes $4 \mu V$ due to the chip temperature increasing from 10°C to 20°C starting from the moment the power supplies are turned on. In the 10-s measurement interval, these temperature-induced effects can easily exceed tens of nanovolts.
- 2. For similar reasons, the device should be well shielded from air currents to eliminate the possibility of thermoelectric effects in excess of a few nanovolts, which would invalidate the measurements.
- 3. Sudden motion in the vicinity of the device should be avoided, as it produces a feedthrough effect that increases observed noise.



APPLICATION INFORMATION

noise testing (continued)



NOTE: All capacitor values are for nonpolarized capacitors only.





APPLICATION INFORMATION

noise testing (continued)

When measuring noise on a large number of units, a noise-voltage density test is recommended. A 10-Hz noise-voltage density measurement correlates well with a 0.1-Hz to 10-Hz peak-to-peak noise reading since both results are determined by the white noise and the location of the 1/f corner frequency.

Figure 35 shows a circuit measuring current noise and the formula for calculating current noise.

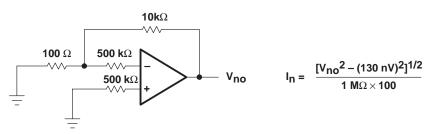


Figure 35. Current Noise Test Circuit and Formula

offset voltage adjustment

The input offset voltage and temperature coefficient of the OP27 and OP37 are permanently trimmed to a low level at wafer testing. However, if further adjustment of VIO is necessary, using a 10-kΩ nulling potentiometer as shown in Figure 36 does not degrade the temperature coefficient α_{VIO} . Trimming to a value other than zero creates an α_{VIO} of $V_{IO}/300 \,\mu$ V/°C. For example, if V_{IO} is adjusted to 300 μ V, the change in α_{VIO} is 1 μ V/°C.

The adjustment range with a 10-k Ω potentiometer is approximately ±2.5 mV. If a smaller adjustment range is needed, the sensitivity and resolution of the nulling can be improved by using a smaller potentiometer in conjunction with fixed resistors. The example in Figure 37 has an approximate null range of $\pm 200 \,\mu$ V.

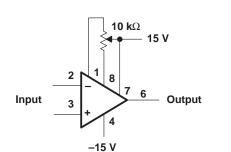


Figure 36. Standard Input Offset Voltage Adjustment

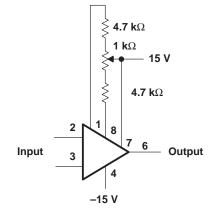


Figure 37. Input Offset Voltage Adjustment With **Improved Sensitivity**

offset voltage and drift

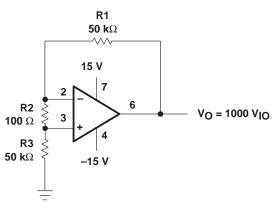
Unless proper care is exercised, thermoelectric effects caused by temperature gradients across dissimilar metals at the contacts to the input terminals can exceed the inherent temperature coefficient $\approx V_{IO}$ of the amplifier. Air currents should be minimized, package leads should be short, and the two input leads should be close together and at the same temperature.



APPLICATION INFORMATION

offset voltage and drift (continued)

The circuit shown in Figure 38 measures offset voltage. This circuit can also be used as the burn-in configuration for the OP27 and OP37 with the supply voltage increased to 20 V, R1 = R3 = 10 k Ω , R2 = 200 Ω , and A_{VD} = 100.



NOTE A: Resistors must have low thermoelectric potential.



unity gain buffer applications

The resulting output waveform, when $R_f \le 100 \Omega$ and the input is driven with a fast large-signal pulse (> 1 V), is shown in the pulsed-operation diagram in Figure 39.



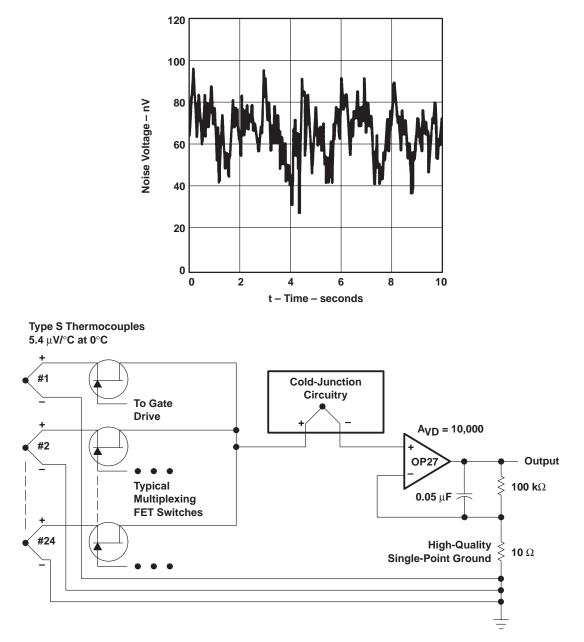
Figure 39. Pulsed Operation

During the initial (fast-feedthrough-like) portion of the output waveform, the input protection diodes effectively short the output to the input, and a current, limited only by the output short-circuit protection, is drawn by the signal generator. When $R_f \ge 500 \ \Omega$, the output is capable of handling the current requirements (load current $\le 20 \ \text{mA}$ at 10 V), the amplifier stays in its active mode, and a smooth transition occurs. When $R_f > 2 \ k\Omega$, a pole is created with R_f and the amplifier's input capacitance, creating additional phase shift and reducing the phase margin. A small capacitor (20 pF to 50 pF) in parallel with R_f eliminates this problem.



APPLICATION INFORMATION

unity gain buffer applications (continued)



NOTE A: If 24 channels are multiplexed per second and the output is required to settle to 0.1 % accuracy, the amplifier's bandwidth cannot be limited to less than 30 Hz. The peak-to-peak noise contribution of the OP27 will still be only 0.11 µV, which is equivalent to an error of only 0.02°C.

Figure 40. Low-Noise, Multiplexed Thermocouple Amplifier and 0.1-Hz To 10-Hz Peak-to-Peak Noise Voltage



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